




<p><b>Searched</b></p> 	<p>Application/Control No.</p> <p>10663901</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>KAKUHARI ET AL.</p>
	<p>Examiner</p> <p>Tran, Mai T</p>	<p>Art Unit</p> <p>2129</p>

Class	SubClass	Date	Examiner
706	16	09/12/2006	mtt
29	745, 747, 844, 851, 861	09/12/2006	mtt
72	21.4	09/12/2006	mtt

U.S. Patent and Trademark Office	Part of Paper No.: 09062006
----------------------------------	-----------------------------

<b>Search Notes</b>  	Application/Control No.  10663901	Applicant(s)/Patent Under Reexamination  KAKUHARI ET AL.
	Examiner Tran, Mai T	Art Unit 2129

Notes	Date	Examiner
EAST (Please see search history printout)	08/01/2006	mtt
ACM Portal (Please see search history printout)	09/12/2006	mtt
Google (Please see search history printout)	09/12/2006	mtt
IEEE (Please see search history printout)	09/12/2006	mtt
U.S. Patent and Trademark Office		Part of Paper No.: 09062006

<b>Interference Searched</b>  	Application/Control No.  10663901	Applicant(s)/Patent Under Reexamination  KAKUHARI ET AL.
	Examiner Tran, Mai T	Art Unit 2129

Class	SubClass	Date	Examiner
-------	----------	------	----------

US-PGPub, USPAT text search  
(Please see interference search  
printout)

9/12/2006

mtt

U.S. Patent and Trademark Office	Part of Paper No.:	09062006
----------------------------------	--------------------	----------